

Green Device Available  
 Super Low Gate Charge  
 Excellent CdV/dt effect decline  
 Advanced high cell density Trench technology

### Product Summary



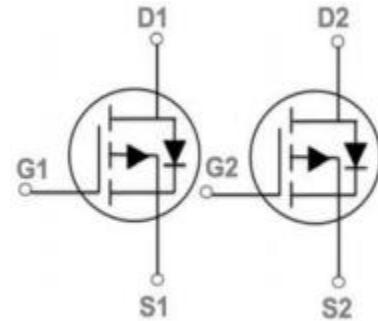
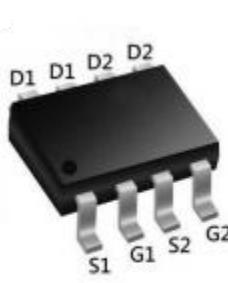
BVDSS	RDS(on)	ID
-30V	18mΩ	-9.5A

### SOP8 Pin Configuration

#### Description

The XXW4805 is the high cell density trenched P-ch MOSFETs, which provide excellent RDS(on) and gate charge for most of the synchronous buck converter applications.

The XXW4805 meet the RoHS and Green Product



### Absolute Maximum Ratings ( $T_A=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain- Source Voltage		-30	V
$V_{GSS}$	Gate- Source Voltage		$\pm 20$	V
$I_D$	Continuous Drain Current	$T_A = 25^\circ\text{C}$	-9.5	A
		$T_A = 100^\circ\text{C}$	-5.9	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		-36	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		25	mJ
$P_D$	Power Dissipation	$T_A = 25^\circ\text{C}$	3.3	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient		38	$^\circ\text{C}/\text{W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to + 150	$^\circ\text{C}$

**Electrical Characteristics ( $T_J=25^\circ C$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain- Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BV_{DSS}$ Temperature Coefficient	Reference to $25^\circ C, I_D=-1mA$	---	-0.022	---	V/ $^\circ C$
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=-10V, I_D=-6A$	---	18	25	$m\Omega$
		$V_{GS}=-4.5V, I_D=-4A$	---	25	42	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.0	---	-2.5	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	4.6	---	$mV/ ^\circ C$
$I_{DSS}$	Drain- Source Leakage Current	$V_{DS}=-24V, V_{GS}=0V, T_J=25^\circ C$	---	---	-1	$uA$
		$V_{DS}=-24V, V_{GS}=0V, T_J=55^\circ C$	---	---	-5	
$I_{GSS}$	Gate- Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=-5V, I_D=-6A$	---	17	---	S
$R_g$	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	---	13	---	$\Omega$
$Q_g$	Total Gate Charge (-4.5V)	$V_{DS}=-15V, V_{GS}=-4.5V, I_D=-6A$	---	12.6	---	$nC$
$Q_{gs}$	Gate- Source Charge		---	4.8	---	
$Q_{gd}$	Gate- Drain Charge		---	4.8	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=-15V, V_{GS}=-10V, R_G=3.3\Omega, I_D=-6A$	---	4.6	---	$ns$
$T_r$	Rise Time		---	14.8	---	
$T_{d(off)}$	Turn-Off Delay Time		---	41	---	
$T_f$	Fall Time		---	19.6	---	
$C_{iss}$	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1MHz$	---	1345	---	$pF$
$C_{oss}$	Output Capacitance		---	194	---	
$C_{rss}$	Reverse Transfer Capacitance		---	158	---	

**Diode Characteristics**

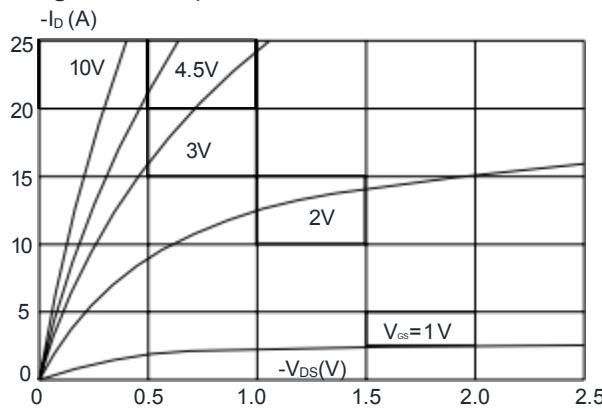
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0V$ , Force Current	---	---	-6.5	A
$I_{SM}$	Pulsed Source Current <sup>2,5</sup>		---	---	-26	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0V, I_S=-1A, T_J=25^\circ C$	---	---	-1.2	V
$t_{rr}$	Reverse Recovery Time	$I_F=-6A, dI/dt=100A/\mu s, T_J=25^\circ C$	---	16.3	---	$ns$
$Q_{rr}$	Reverse Recovery Charge		---	5.9	---	$nC$

Note :

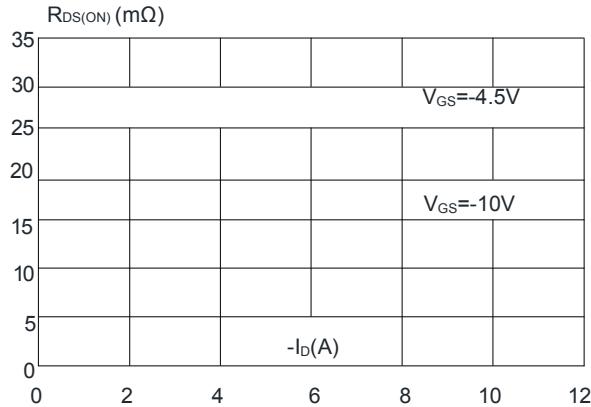
1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2 OZ copper.
2. The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
3. The EAS data shows Max. rating . The test condition is  $V_{DD}=-25V, V_{GS}=-10V, L=0.1mH, I_{AS}=-38A$
4. The power dissipation is limited by  $150^\circ C$  junction temperature
5. The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

## Typical Performance Characteristics

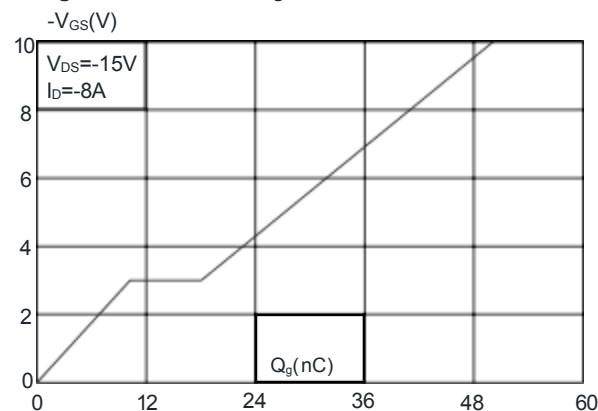
**Figure1 :** Output Characteristics



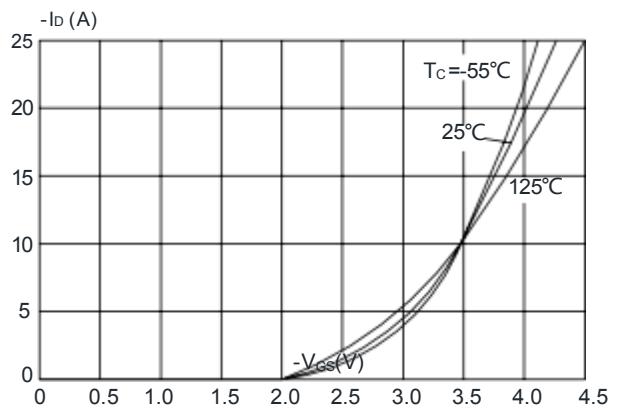
**Figure 3:** On-resistance vs. Drain Current



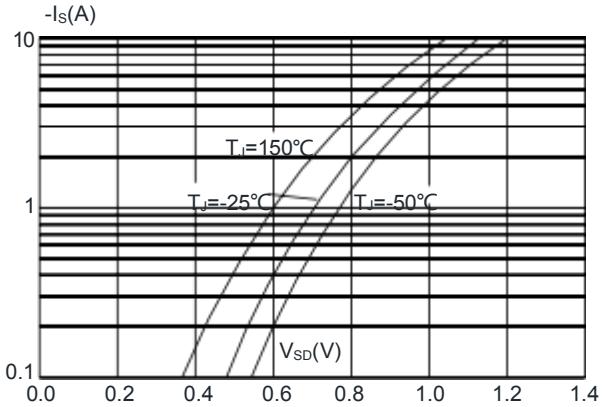
**Figure 5:** Gate Charge Characteristics



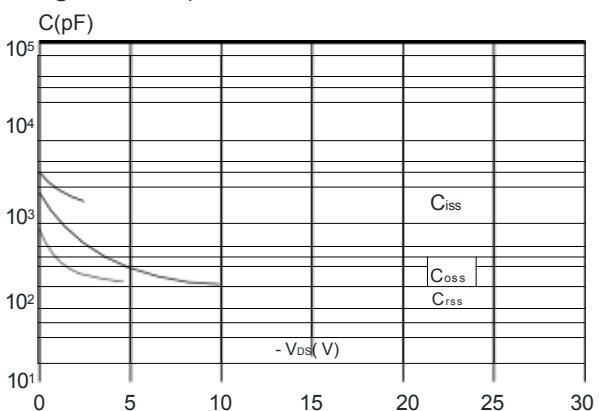
**Figure 2 :** Typical Transfer Characteristics



**Figure 4 :** Body Diode Characteristics

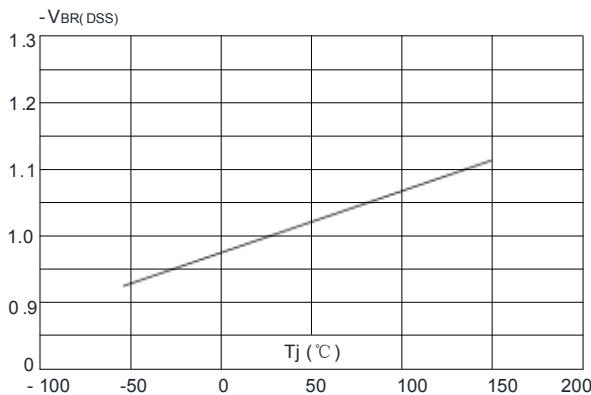


**Figure 6:** Capacitance Characteristics

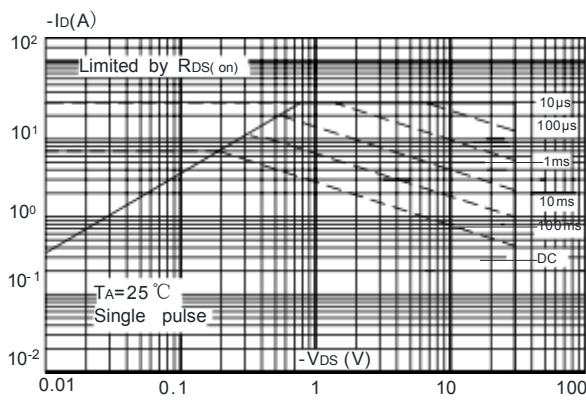


**Dual P-Ch 30V Fast Switching MOSFETs**

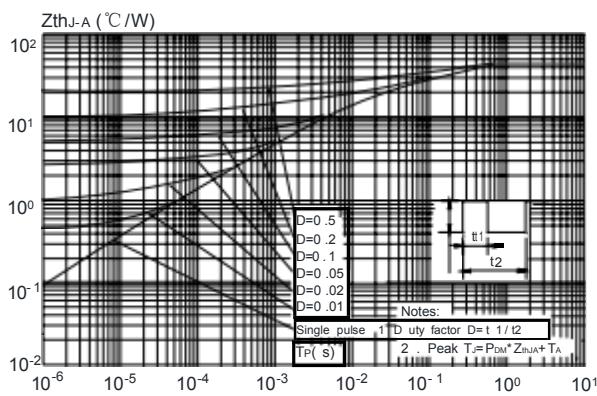
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



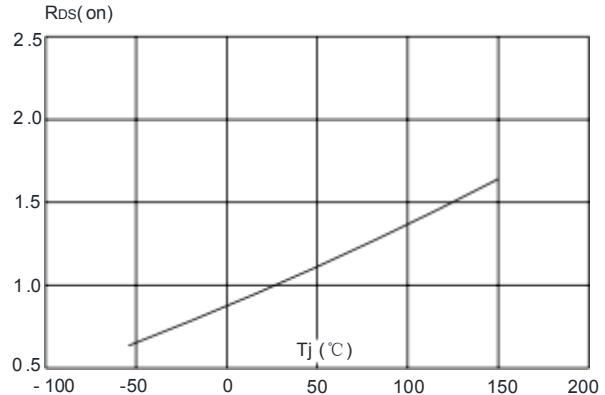
**Figure 9:** Maximum Safe Operating Area



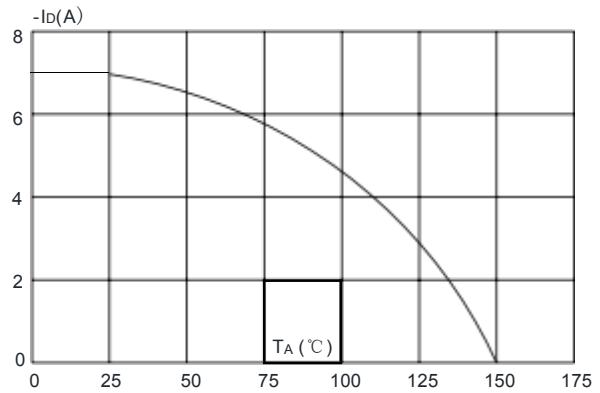
Maximum Effective  
Transient Thermal Impedance, Junction-to-Ambient

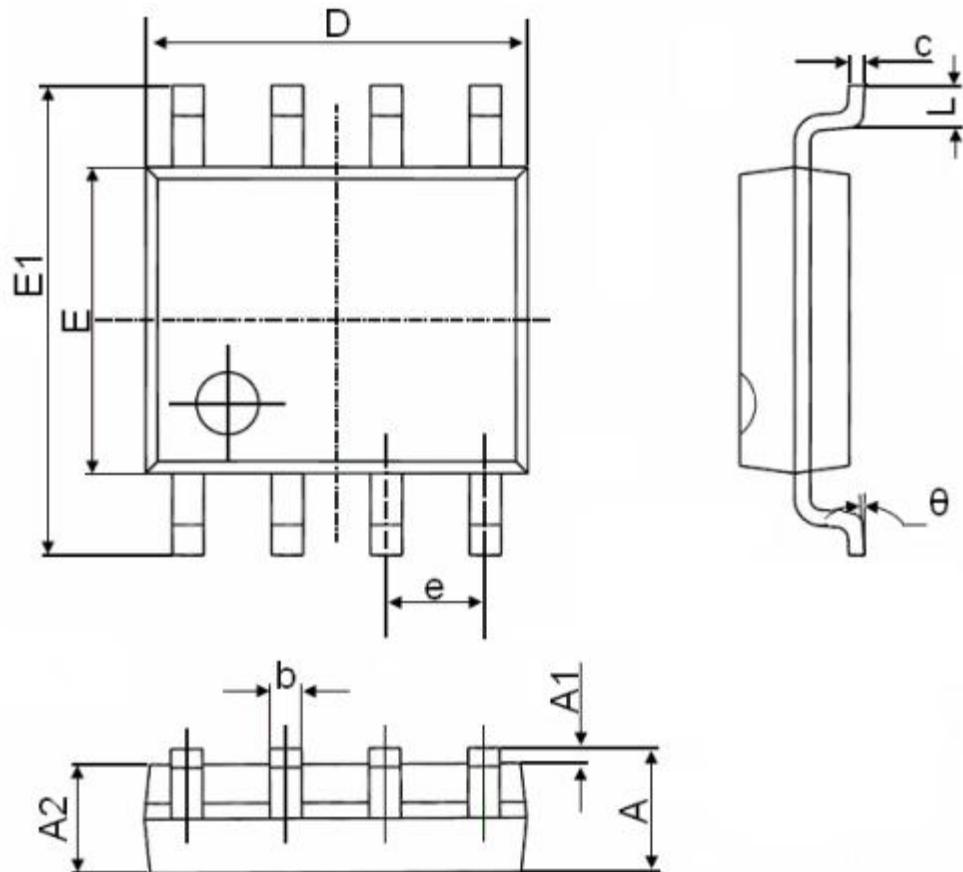


**Figure 8:** Normalized on Resistance vs. Junction Temperature



**Figure 10:** Maximum Continuous Drain Current vs. Ambient Temperature



**Package Mechanical Data- SOP-8**

 COMMON DIMENSIONS  
 (UNITS OF MEASURE=mm)

SYMBOL	MIN	NOM	MAX
A	1.40	1.60	1.80
A1	0.05	0.15	0.25
A2	1.35	1.45	1.55
b	0.30	0.40	0.50
c	0.153	0.203	0.253
D	4.80	4.90	5.00
E	3.80	3.90	4.00
E1	5.80	6.00	6.20
L	0.45	0.70	1.00
θ	2°	4°	6°
L1	1.04 REF		
e	1.27 BSC		
R1	0.07 TYP		
R2	0.07 TYP		